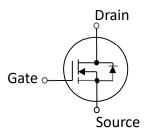


### 30V, -10A (1) P-Channel MOSFET

- Advanced Trench Device Design and Processes
- High Reliability Capability
- Sampled CP Probing and Inking





Electrical Characteristics in C/P Test (T $_{ m J}$ at 25 $^{ m  extsf{C}}$ )						
Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Condition
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	_	ı	-30	V	V <sub>GS</sub> =0V, I <sub>D</sub> =-250μA
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	_	6.3	7.6	mΩ	V <sub>GS</sub> =-10V, I <sub>D</sub> =-1A(2)
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	_	10.7	13.2	mΩ	V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-1A(2)
V <sub>GS (th)</sub>	Gate Threshold Voltage	-2.5	_	-1	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250μA
I <sub>DSS</sub>	Drain-to-Source Leakage Current	-1	_	_	μA	V <sub>DS</sub> =-30V, V <sub>GS</sub> =0V
I <sub>GSS</sub>	Gate-to-Source Leakage Current	-100	_	100	nA	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature	-55℃ to 150℃ Max.				

Mechanical Data			Die Drawing			
Chip Size	2234 µm X 1380 µm		1380.2ur	n (		
Gate Pad Size	174 μm X 170 μm		1		<b>n</b> î	
Source Pad Size	2150 μm X 1296 μm					
Scribe Line Width	60 µm	<b></b>		129		
Wafer Thickness	150 μm			1295.8um		
Wafer Diameter	200 mm		214		2234.3um	
Gross Die	8682 EA		2149.9um		3um	
Source Metallization	Al-Cu (4µm typical)					
Drain Metallization	Ti-Ni-Ag					
Passivation	N/A	17 170um				
Recommended Storage Environment	Store in original container, in dry nitrogen, 6 months at ambient temperature of 23°C ± 3°C	∯ <sup>4</sup> um			<b>y</b>	

<sup>(1)</sup> This characteristic assumes the die is assembled in SOP-8 package. Actual performance may degrade when assembled.

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<sup>(2)</sup> Pulse Width tp = < 1 mS, Duty Cycle < 2%.

Specific Assembly Info	Die Drawing			
Package Type	SOP-8	1380.2um		
Die Attach Method	Soft solder	$ \leftarrow$		
Soft Solder Composition	Pb,Sn,Ag	1295.8um		
Gate Wire Bonding	Cu, 2 mil x1	2234.3um 2149.9um		
Source Wire Bonding	Cu, 2 mil x 8	3		
Molding Compound Manufacturer	G700HF	1744		
Solder Plating Composition	Pure Tin			

Position			Bonding Diagram Top View			
	X (um)	Y (um)	ZERO			
ZERO	0	0	<b>5</b>			
ТОР	2234.3	1380.2				
S1	52.2	52.2				
S2	2182.1	1328				
S3	2030.45	207.15				
G1	2046.45	191.15	92 SZ •			
G2	2217.1	17.2	ТОР			



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Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Condition
I <sub>DSS</sub>	Drain-to-Source Leakage Current	-1	_	_	μA	V <sub>DS</sub> =-30V, V <sub>GS</sub> =0V
I <sub>GSSF</sub>	Gate-to-Source Leakage Current	_	_	100	nA	V <sub>DS</sub> =0V, V <sub>GS</sub> =+20V
I <sub>GSSR</sub>	Gate-to-Source Leakage Current	-100	_	_	nA	V <sub>DS</sub> =0V, V <sub>GS</sub> =-20V
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	_	_	-30	V	V <sub>GS</sub> =0V, I <sub>D</sub> =-250μA
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	_	_	-30	V	V <sub>GS</sub> =0V, I <sub>D</sub> =-1mA
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	_	_	10.5	mΩ	V <sub>GS</sub> =-10V, I <sub>D</sub> =-10A
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	_	_	16	mΩ	V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-10A
V <sub>GS (th)</sub>	Gate Threshold Voltage	-2.5	_	-1	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250μA
V <sub>SD</sub>	Body Diode Forward Voltage	-1.1	_	_	V	V <sub>GS</sub> =0V, I <sub>SD</sub> =-10A
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature	-55	_	150	$^{\circ}\!$	



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